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| L5 same wafer | 3 | |

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Search History

DATE: Tuesday, March 28, 2006 Printable Copy Create Case

| Set Name side by side | | Hit Count | Set Name result set |
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| DB=U | SPT; PLUR=YES; OP=OR | | |
| <u>L6</u> | L5 same wafer | 3 | <u>L6</u> |
| <u>L5</u> | L4 same interconnect\$5 | 28 | <u>L5</u> |
| <u>L4</u> | "electronic device" same ("temperature" near4 sens\$5) | 729 | <u>L4</u> |
| <u>L3</u> | L1 same (conduct\$5) | 29 | <u>L3</u> |
| <u>L2</u> | L1 and (conduct\$5) | 164 | <u>L2</u> |
| <u>L1</u> | foamed same hydrophobic | 352 | <u>L1</u> |

END OF SEARCH HISTORY